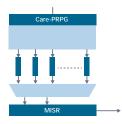
Synopsys SLM BIST IP delivers a solution for in-system self-test of digital designs where functional safety is critical, such as automotive, medical, and aerospace applications. Synopsys SLM BIST family consists of LBIST and XLBIST variants. LBIST is targeted for analog and mixed-signal designs with limited digital content. XLBIST has X-tolerant capability with compression making it suitable for large digital designs. Both products are certified for ISO26262 standard, targeting the most stringent ASIL-D requirements. Synopsys TestMAX ATPG is used to generate seed and signature needed by BIST IP.



- Small area for Big A/Small d designs
- Highly configurable
- Manufacturing test
- Power-on system test
- In-system test

Seed	d from ATPG	
Pattern Generation	Phase Shifter Dynamic Power Saving	
	MISR	

## **Synopsys**°

The SLM XLBIST architecture also supports deterministic pattern generation with TestMAX ATPG, eliminating the need for separate